



ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18
Stylesheet Version v18.0

Title of Invention	NON-VOLATILE MEMORY ARRAY WITH SIMULTANEOUS WRITE AND ERASE FEATURE						
Application Number: 10/773059							
Confirmation Number: 5441							
First Named Applicant: Bohumil Lojek							
Attorney Docket Number: ATM-275							
Art Unit: 2818 2824							
Search string: (4334292 or 4432075 or 4821236 or 4890259 or 5126967 or 5990512 or 6125053).pn.							
US Patent Documents							
Note: Applicant is not required to submit a paper copy of cited US Patent Documents							
init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
AGS	1	4334292	1982-06-08	Harish N Kotecha	A1	365	182
AGS	2	4432075	1984-02-14	Boaz Eitan	A1	365	185
AGS	3	4821236	1989-04-11	Yutaka Hayashi et al.	A1	365	185
AGS	4	4890259	1989-12-26	Richard T. Simko	A1	365	45
AGS	5	5126967	1992-06-30	Richard Simko	A1	365	45
AGS	6	5990512	1999-11-23	Christopher J. Diorio et al.	A1	257	314
AGS	7	6125053	2000-09-26	Christopher J. Diorio et al.	A1	365	185.03
Signature 							
Examiner Name				Date			
ALEXANDER SOFOCLEOUS				8/24/2005			

FORM PTO-1449	Atty. Docket No. ATM-275	Serial No. 10/773,059
LIST OF PRIOR ART CITED BY APPLICANT	Applicants: Bohumil Lojek	
	Filing Date: Feb. 4, 2004	Group: 2818



U.S. PATENT DOCUMENTS

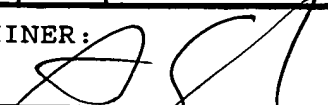
Examiner Initial*	Document Number	Publ. Date	Name	Class	Sub Class	Filing Date
AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						

FOREIGN PATENT DOCUMENTS

Examiner Initial*	Document Number	Publ. Date	Country	Class	Sub Class	Translation Yes No
AK						
AL						
AM						
AN						

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AGS	AO	B. Eitan et al. (School of Applied Science and Technology, The Hebrew University of Jerusalem, Jerusalem, Israel), <i>Impact Ionization at Very Low Voltages in Silicon</i> , J. Appl. Phys. 53(2), February 1982, pp. 1244-1247.
	AP	

EXAMINER:  ALEXANDER SOFOCLEOUS	DATE CONSIDERED: 8/24/2005
--	-------------------------------

*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.